

IN THE CLAIMS

(1) Please rewrite claim 1 as follows:

1 1. (Amended) An apparatus for testing an integrated circuit to determine if 1/f
2 noise of a circuit to be tested on said integrated circuit is within specifications,
3 comprising:

4 a. a mechanism for applying a preselected offset inside a chopper stabilized
5 circuit forming part of said circuit to be tested; and

6 b. a circuit for checking whether the output of said chopper stabilized circuit is
7 within a predetermined offset specification for the chopper stabilized circuit.

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(2) Please rewrite claim 2 as follows:

1 2. (Amended) Apparatus of claim 1 in which said preselected offset has a value
2 greater than expected in normal use with the chopper stabilized circuit.

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(3) Please rewrite claim 3 as follows:

1 3. (Amended) Apparatus of claim 1 in which the circuit to be tested passes a 1/f
2 noise test if the output of the chopper circuit is within the predetermined offset
3 specification.

(4) Please rewrite claim 5 as follows:

1 5. (Amended) A method for testing an integrated circuit to determine if 1/f noise
2 of a circuit to be tested on said integrated circuit is within specifications comprising:

3 a. applying a preselected offset inside a chopper stabilized circuit forming part of
4 said circuit to be tested; and

5 b. checking whether the out put of said chopper stabilized circuit is within a
6 predetermined offset specification for the chopper stabilized circuit.

(5) Please rewrite claim 6 as follows:)

6. (Amended) Method of claim 5 in which said preselected offset has a value greater than expected in normal use with the chopper stabilized circuit.

(6) Please rewrite claim 7 as follows:)

7. (Amended) Method of claim 5 in which the circuit to be tested passes a 1/f noise test if the output of the chopper stabilized circuit is within the predetermined offset specification.

(7) Please cancel claim 10 without prejudice or disclaimer.

(8) Please rewrite claim 11 as follows:

11. (Amended) A method of testing an integrated circuit comprising:
(a) external to the circuit, observing an output of a chopper stabilized circuit; and
(b) external to the circuit, controlling the offset of the chopper stabilized circuit.

(9) Please rewrite claim 12 as follows:)

12. (Amended) The method of claim 11 comprising using offset removal as a surrogate for 1/f noise performance of the chopper stabilized circuit.

(10) Please add new claim 13 as follows:

13. (New) The method of claim 12 wherein the circuit under test passes a 1/f noise test if the output of the chopper stabilized circuit is within a predetermined offset specification.

(11) (Please add new claim 14 as follows:)

14. (New) An apparatus for testing an integrated circuit to determine if said integrated circuit is within specifications comprising:

a. a mechanism for selectively adding additional offset, while the test is conducted, inside a chopper stabilized circuit forming part of said circuit to be tested; and

b. a circuit for checking whether the output of said chopper stabilized circuit is within a predetermined limit.

(12) (Please add new claim 15 as follows:)

15. (New) Apparatus of claim 14 in which the additional offset combined with any internal offset of the chopper stabilized circuit has a value greater than expected in normal use with a chopper stabilized circuit.

(13) (Please add new claim 16 as follows:)

16. (New) A method for testing an integrated circuit to determine if said integrated circuit is within specifications, comprising:

a. selectively adding additional offset, while the test is conducted, inside a chopper stabilized circuit forming part of said circuit to be tested; and

b. checking whether the output level of said chopper stabilized circuit is within a predetermined limit.